

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	97	("5801965" "6438438" "6177287" "5943437" "6347150" "5659172" "5917935" "5966459" "4532650" "5325445" "6222935" "6222935" "6104835" "4587617" "6456899" "5513275" "5394481" "5204910" "4449818" "6167150" "6334097" "4173441" "5734742" "5862055" "5798830" "6466895" "5414270" "5515159" "6057926" "6092059" "6171874" "5263094" "5745239" "6200823" "5253306" "4989258" "6353222" "5602646" "5335293" "6341241" "6473665" "4308959" "6166393" "5808735" "5761337" "6259960" "6185511" "6233352" "5182775" "5844603").pn.	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/01 20:27
S2	17	("4253768" "4587617" "5129009" "5210041" "5219765" "5240866" "5301248" "5325445" "5426506" "5434790" "5440649" "5479252" "5801965" "5923430" "5982921" "6014461" "6021380").PN.	USPAT	OR	ON	2003/03/03 17:02
S3	2	((("5801965" "6438438" "6177287" "5943437" "6347150" "5659172" "5917935" "5966459" "4532650" "5325445" "6222935" "6222935" "6104835" "4587617" "6456899" "5513275" "5394481" "5204910" "4449818" "6167150" "6334097" "4173441" "5734742" "5862055" "5798830" "6466895" "5414270" "5515159" "6057926" "6092059" "6171874" "5263094" "5745239" "6200823" "5253306" "4989258" "6353222" "5602646" "5335293" "6341241" "6473665" "4308959" "6166393" "5808735" "5761337" "6259960" "6185511" "6233352" "5182775" "5844603").pn.) and (short adj defects)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:34
S4	0	"circuit pattern short defects"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:35
S5	0	"circuit pattern open defects"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:36

EAST Search History

S6	23627	semiconductor and inspection	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:37
S7	741	(semiconductor and inspection) and classification	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:37
S8	3	((semiconductor and inspection) and classification) and reclassification	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:49
S9	7	"5946213".URPN.	USPAT	OR	ON	2003/03/03 17:44
S10	387	209/44.1	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:49
S11	543	209/571	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:49
S12	563	209/573	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:49
S13	70	209/44.4	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:50
S14	75528	"209"/\$.ccls.	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:51
S15	349	"209"/\$.ccls. and semiconductor	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:51
S16	91	("209"/\$.ccls. and semiconductor) and inspection	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 17:59
S17	374	382/152	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 15:59
S18	693	382/149	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 18:00

EAST Search History

S19	221	382/149 and short	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 18:00
S20	8	(382/149 and short) and (short adj defect)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 18:12
S21	7	(semiconductor and inspection) and (kill adj ratio)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 19:28
S22	4	"6338001"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/03/03 19:28
S23	4	"6338001"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/08/01 13:28
S24	77	"automatic defect classification"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/08/01 13:28
S25	0	"automatic defect classification" and (voltage adj contrast)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/08/01 13:29
S26	8	"automatic defect classification" and voltage	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/08/01 13:33
S27	0	"automatic defect classification" and (voltage adj defect)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/08/01 13:33
S28	31	wafer and (voltage adj defect)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/08/01 13:38
S29	130	wafer and (voltage adj contrast)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/08/01 13:38
S30	52	(wafer and (voltage adj contrast)) and inspection	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2003/08/01 13:39

EAST Search History

S31	971	382/149	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/01 20:27
S32	0	S31 and (right adj detector)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/01 20:27
S33	4	S31 and (right near9 detector)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/04/01 20:28
S34	1259	382/145	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 15:59
S35	275	382/146	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:00
S36	648	382/147	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:00
S37	264	382/148	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:00
S38	1180	382/149	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:04
S39	364	382/150	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:00
S40	2242	S34 or S35 or S36 or S37 or S38 or S39	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:04
S41	266	S40 and ((display displaying displays displayed) same defect) same (image images)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/03 14:56
S42	0	khoi-tran.XA.	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:55

EAST Search History

S43	0	khoi-tran.XA.	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:55
S44	37396	"700"/\$.ccls.	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:56
S45	358	S44 and khoi	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:59
S46	84	S45 and feed	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:57
S47	3	S46 and farm	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:56
S48	37565	"221"/\$.ccls.	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:57
S49	95	S48 and khoi	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:57
S50	28	S49 and feed	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:58
S51	0	khoi-tran.XA.	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:58
S52	0	"khoi-tran.XA"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:58
S53	0	khoi adj tran	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:59
S54	0	S45 and agricultur	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 16:59

EAST Search History

S55	6	S45 and agriculture	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 17:00
S56	6	S45 and agricultural	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 17:01
S57	37396	"700"/\$.ccls.	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 17:02
S58	14	S57 and (animal adj feed)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 17:01
S59	49	S57 and bunker	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 19:23
S60	0	S57 and (feed adj bunker)	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 17:03
S61	1	"20020087231"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/02 19:23
S62	12	"6701259"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/03 16:26
S63	5	"6456899"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/03 16:30
S64	22	"5761337"	USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/04/03 16:30
S65	1355	semiconductor and criticality	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/11/28 13:02

EAST Search History

S66	1756532	semiconductor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/11/28 13:02
S67	1912123	semiconductor or wafers	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/11/28 13:02
S68	1532	S67 and criticality	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/11/28 13:02
S69	8683	defect near types	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/11/28 13:03
S70	59	S68 and S69	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/11/28 13:03
S71	52	S70 and images	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/11/28 13:03
S72	7	("5761337" "5801965" "5841893" "5966459" "6496596" "6535776" "6597381").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/11/28 15:44
S73	30	("5841893").URPN.	USPAT	OR	ON	2006/11/28 16:01